



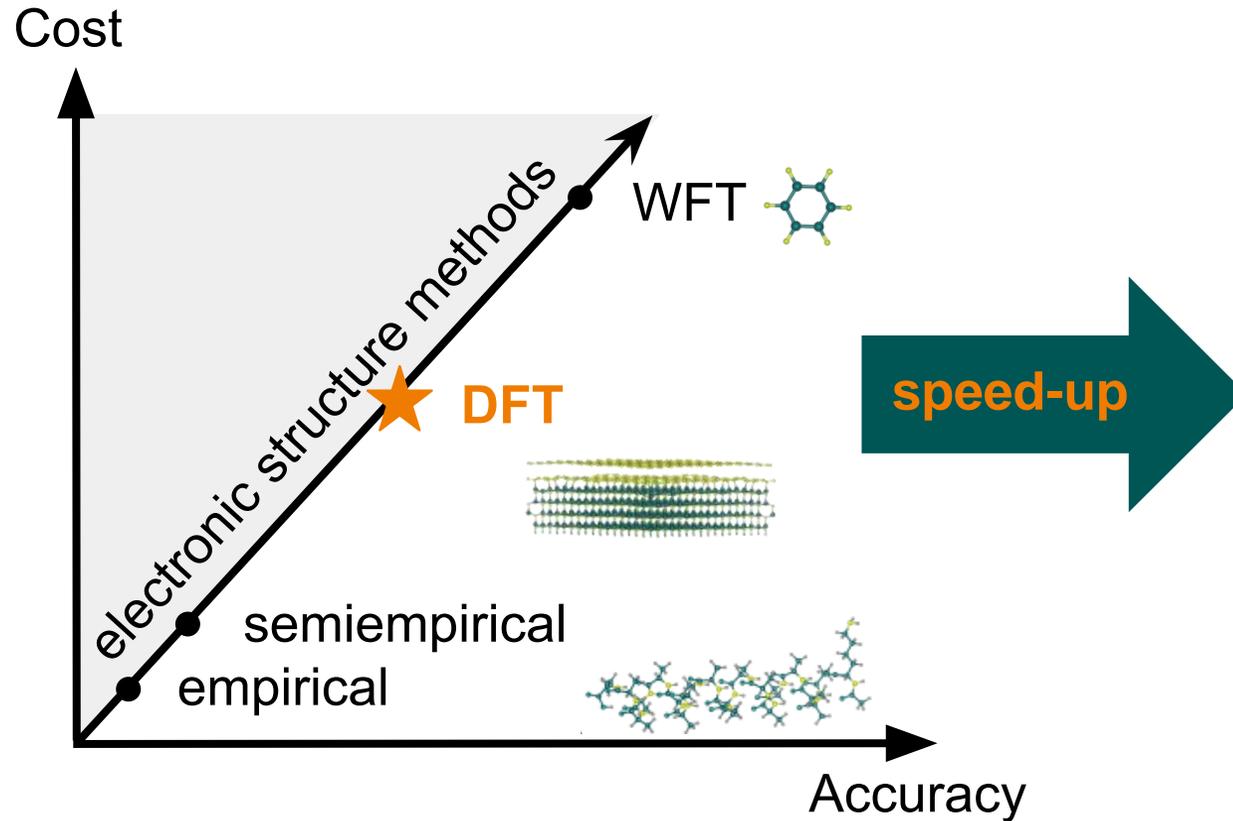
FAST GEOMETRY OPTIMIZATION
OF LARGE-SCALE SYSTEMS
WITH SMALL NUMERICAL BASIS SETS

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DFT – THE WORKHORSE OF MATERIALS MODELLING



small basis + correction

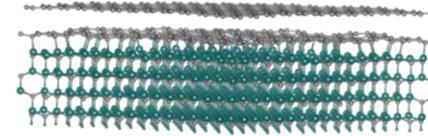


- fast
- robust
- accurate

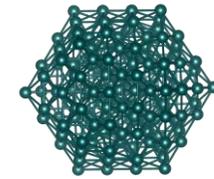


SMALL BASIS + CORRECTION IN MATERIALS MODELLING AREAS OF APPLICATIONS

- **systems with hundreds of atoms**
speed-up molecular dynamics,
geometry optimizations etc.
use in composite methods
- **systems with ≥ 1000 of atoms**
enable large-scale geometry
optimization at DFT level



surfaces/interfaces

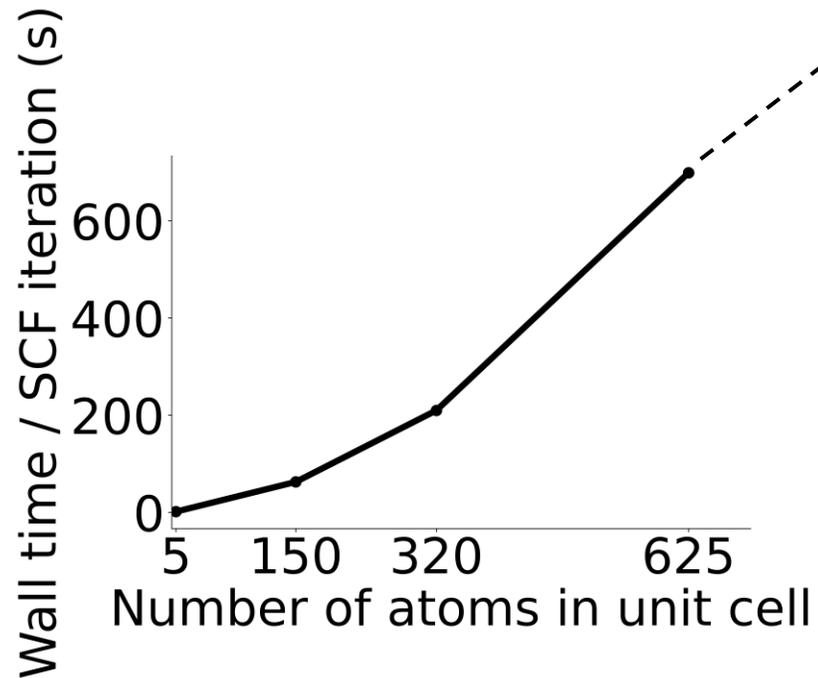


nanoparticles



KS-DFT BOTTLENECK

FHI-aims, PBE
example CsPbBr₃



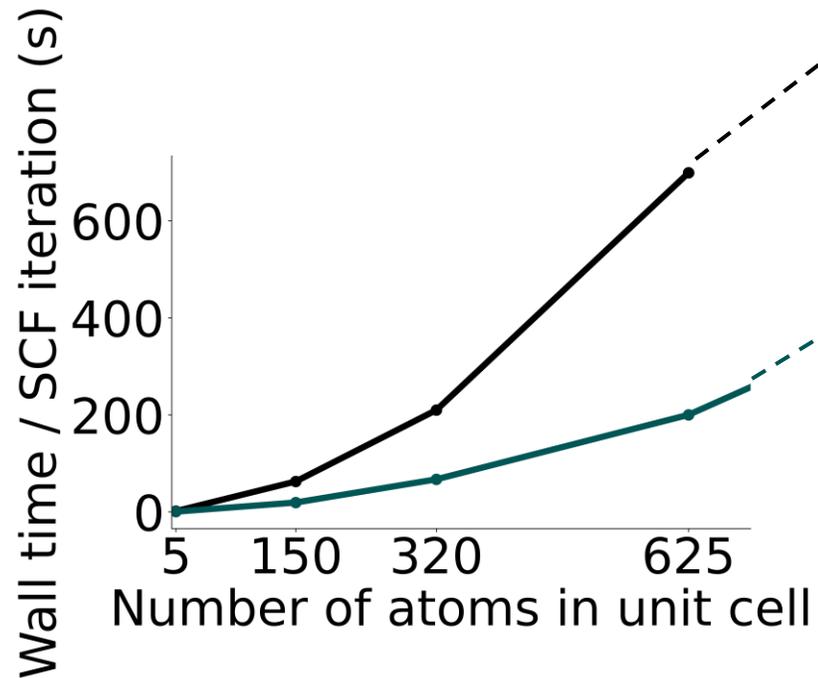
basis-set size: converged ('tight')
cubic-scaling $O(N^3)$ bottleneck



ENABLE LARGE-SCALE COMPUTATIONS WITH SMALL BASIS SET

FHI-aims, PBE

example CsPbBr_3



basis-set size: converged ('tight')

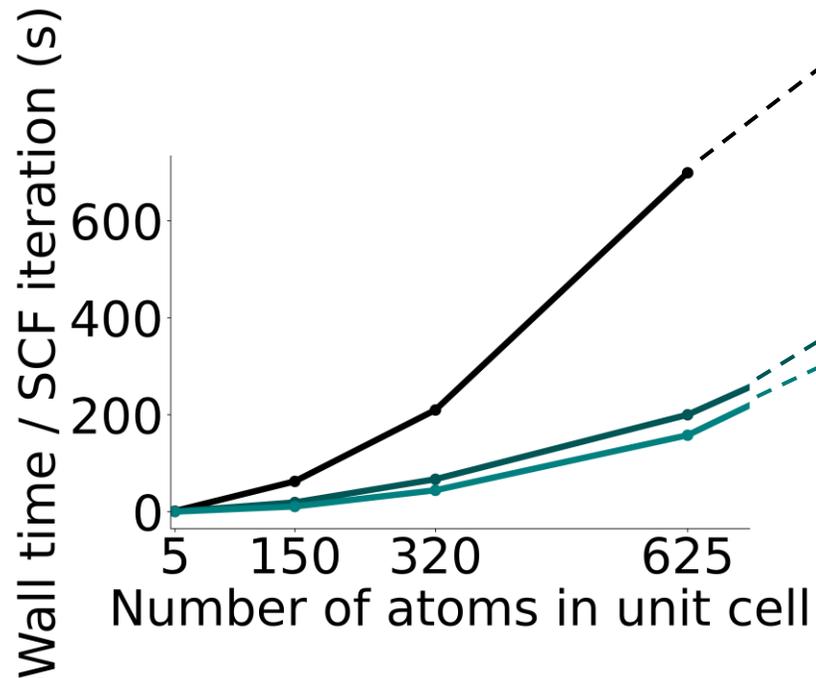
increase accessible system size with:

(1) basis-set size: 'min+s'



ENABLE LARGE-SCALE COMPUTATIONS WITH SMALL BASIS SET

FHI-aims, PBE
example CsPbBr₃



basis-set size: converged ('tight')

increase accessible system size with:

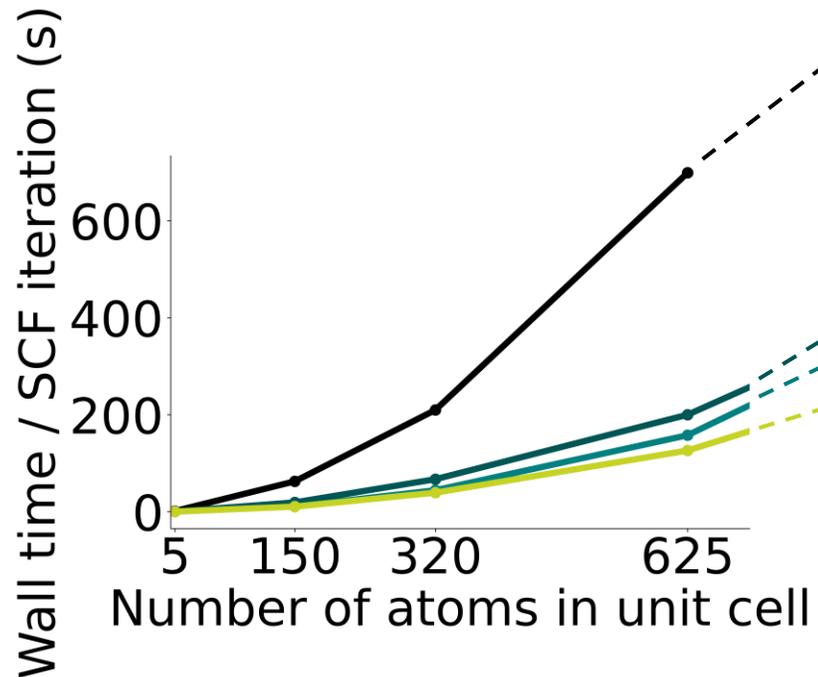
(1) basis-set size: 'min+s'

+ (2) frozen core approximation [1]



ENABLE LARGE-SCALE COMPUTATIONS WITH SMALL BASIS SET

FHI-aims, PBE
example CsPbBr₃



basis-set size: converged ('tight')

increase accessible system size with:

(1) basis-set size: 'min+s'

+(2) frozen core approximation [1]

+(3) 'light' grid settings

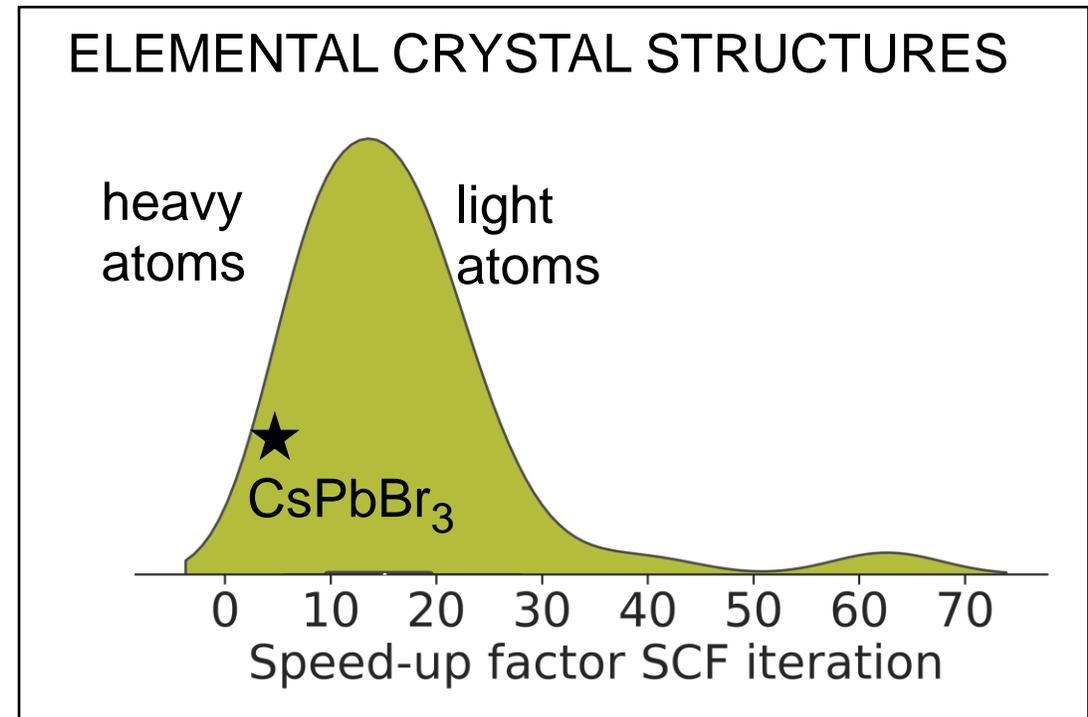
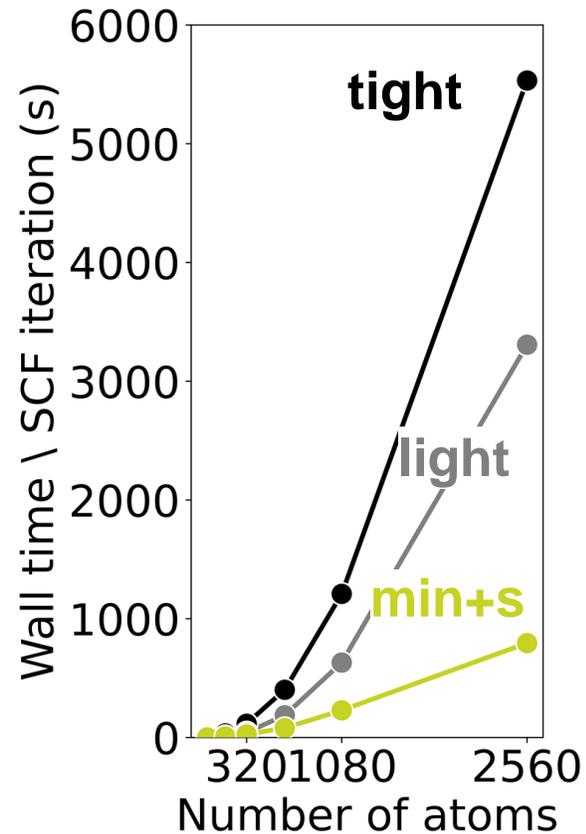


PERFORMANCE SMALL BASIS SET

CsPbBr₃ WITH BASIS SET REDUCTION TO 53%

Time consumption $\sim O(N^3)$

100% \rightarrow 21%



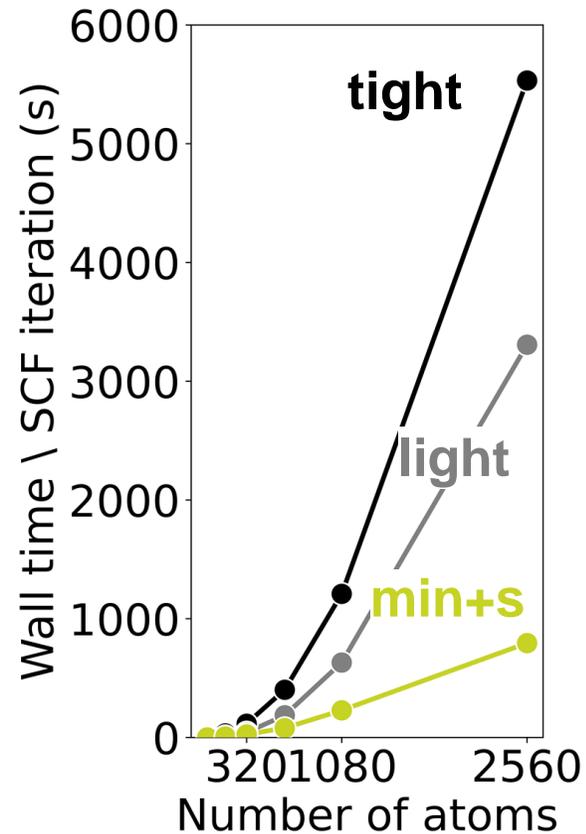


PERFORMANCE SMALL BASIS SET

CsPbBr₃ WITH BASIS SET REDUCTION TO 53%

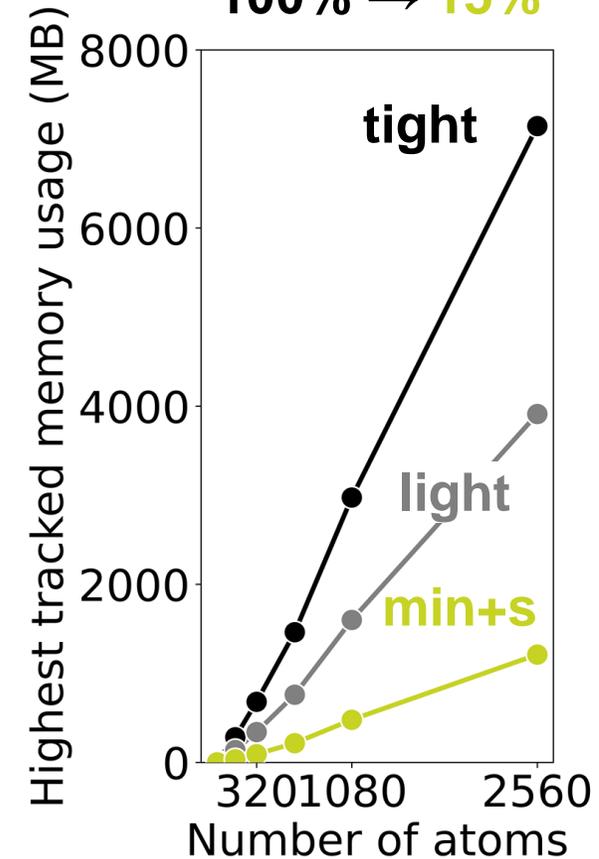
Time consumption $\sim O(N^3)$

100% → 21%



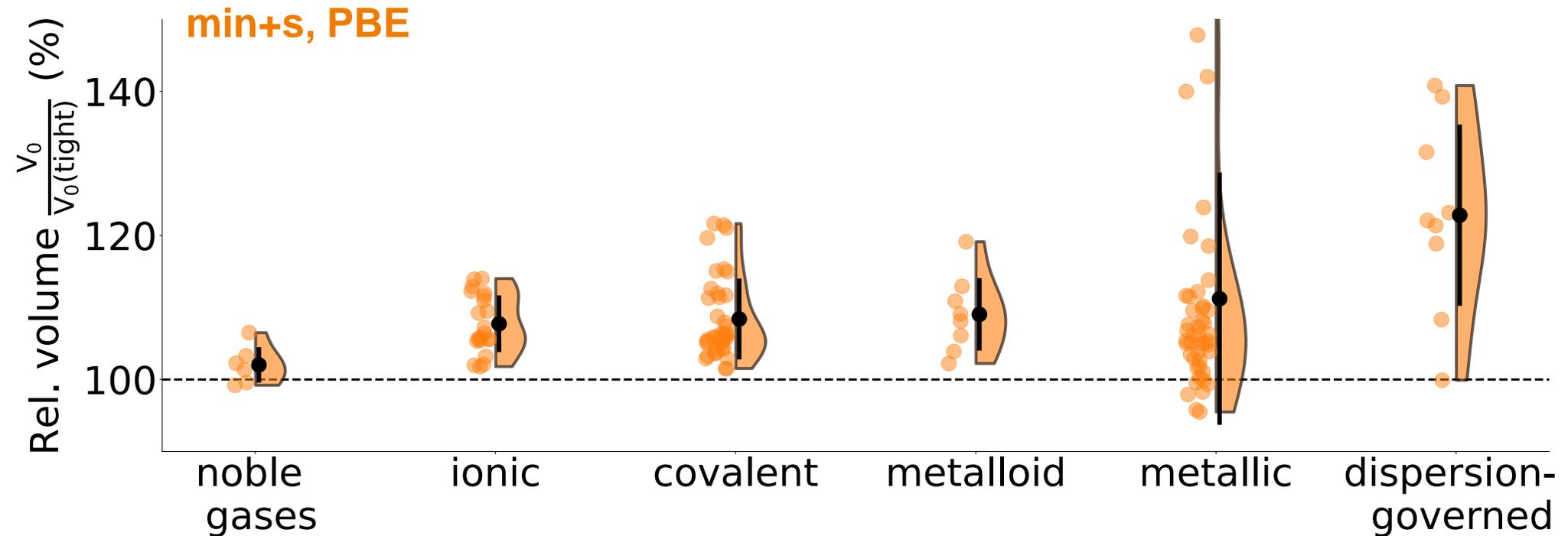
Memory usage $\sim O(N)$

100% → 15%





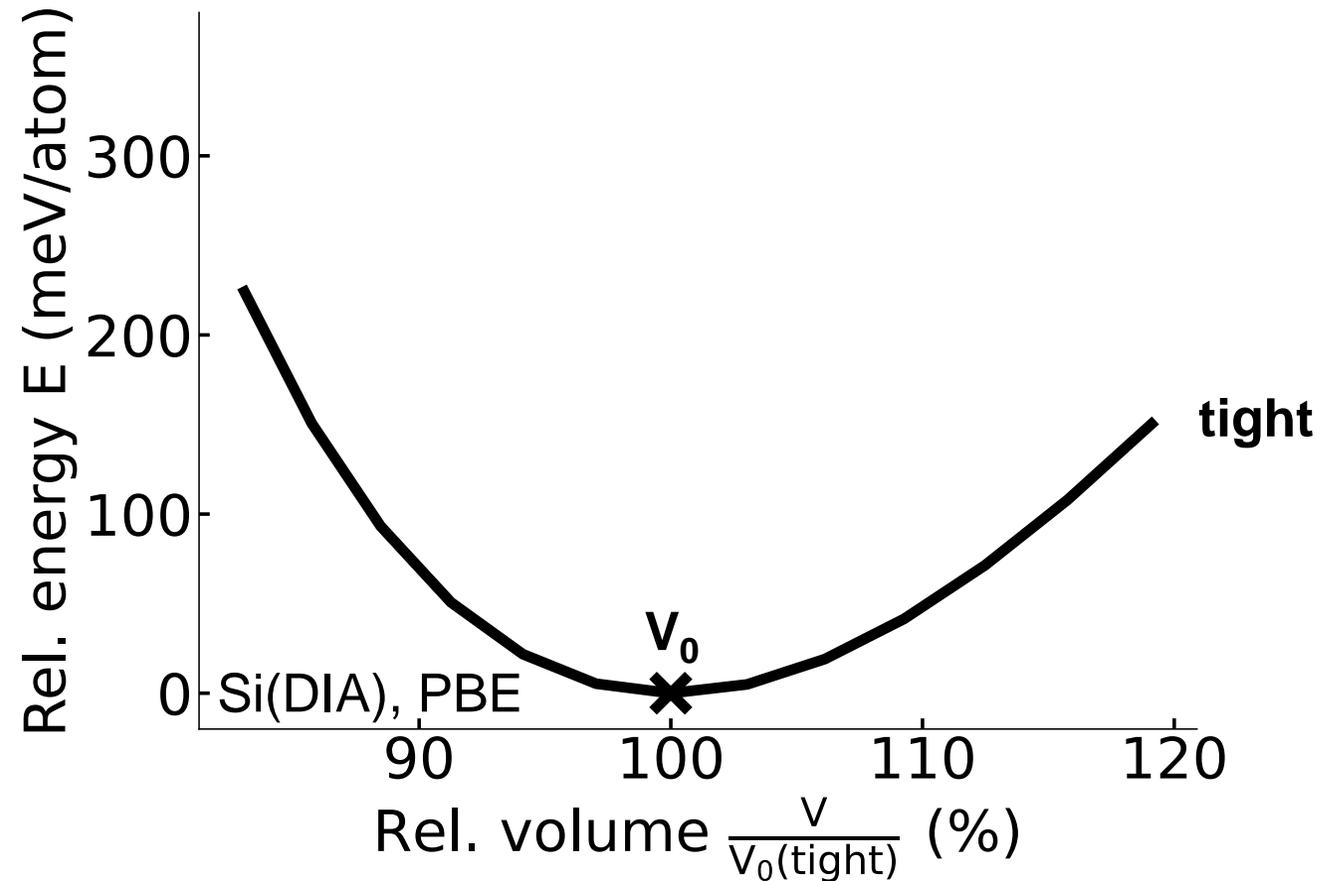
WHY NOT USE SMALL BASIS SETS ON A REGULAR BASIS ? SMALL BASIS SET ERROR





MEASURE OF BASIS SET ERROR IN BULK SYSTEMS

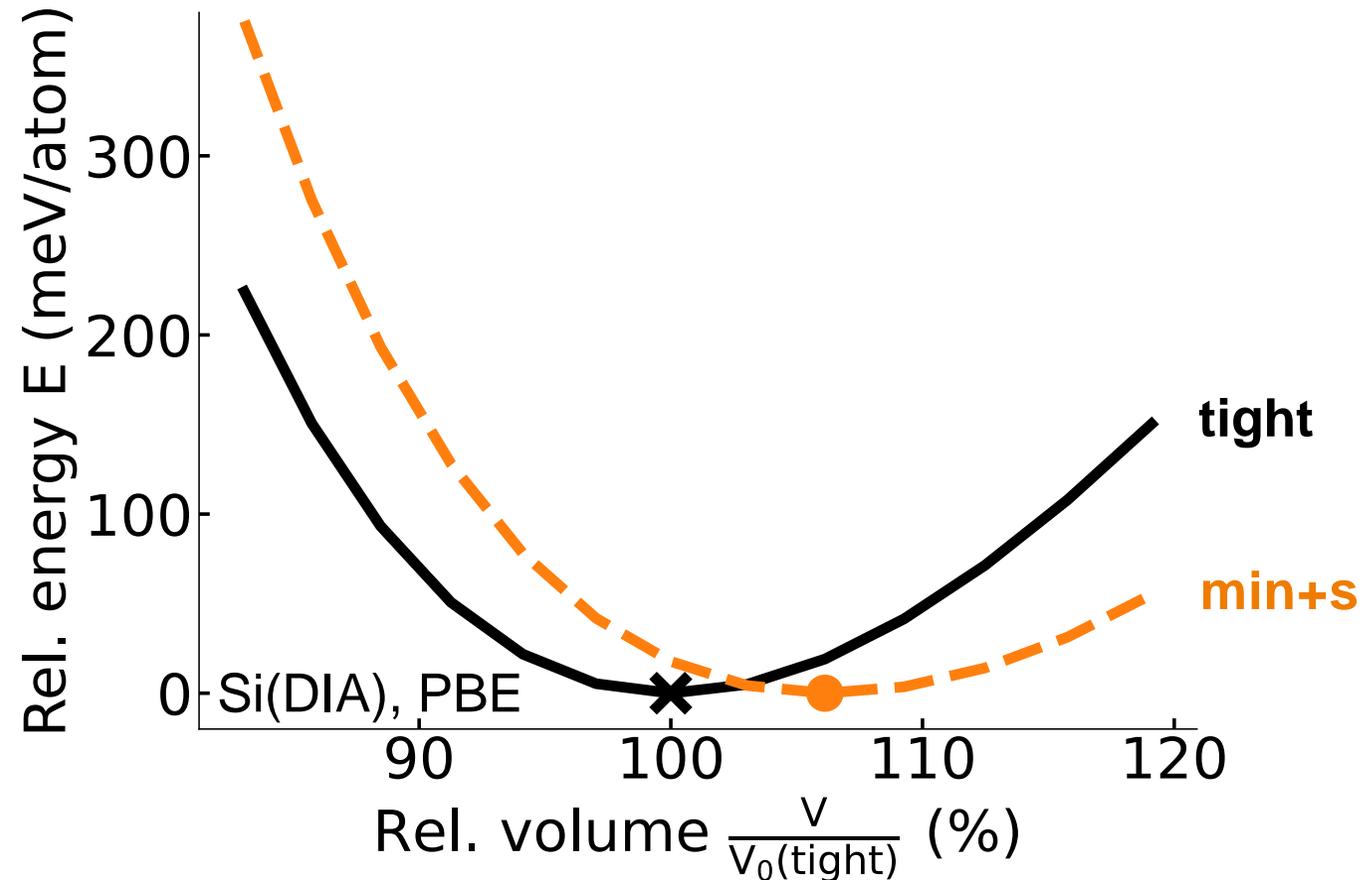
Bulk properties V_0 , E_0 , B , B_p from E-V curve





MEASURE OF BASIS SET ERROR IN BULK SYSTEMS

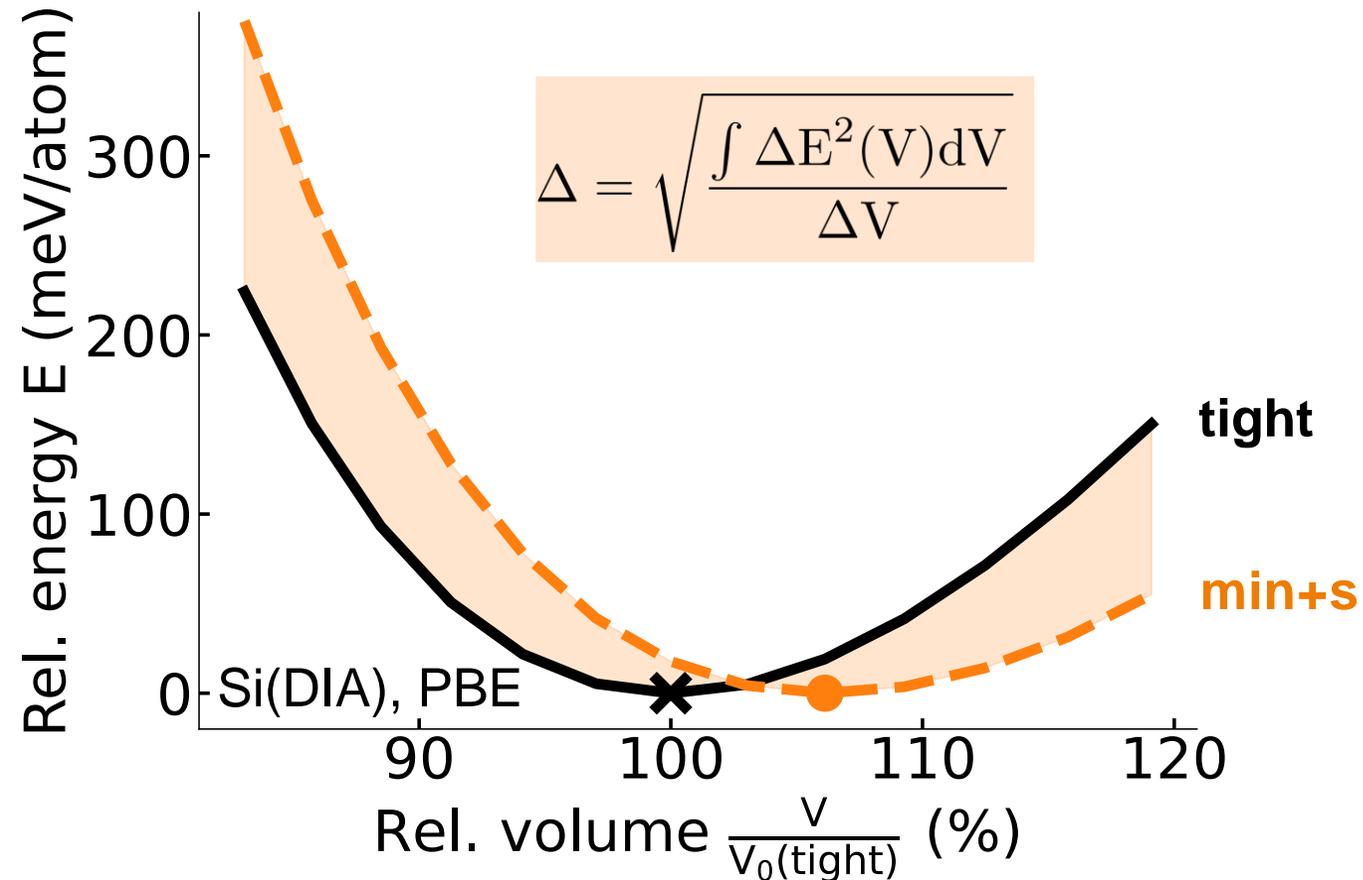
Small basis set alters V_0 , E_0 , B , B_p and shape of E-V curve





MEASURE OF BASIS SET ERROR IN BULK SYSTEMS

Similarity to “tight” E-V curve with Δ -value [2]

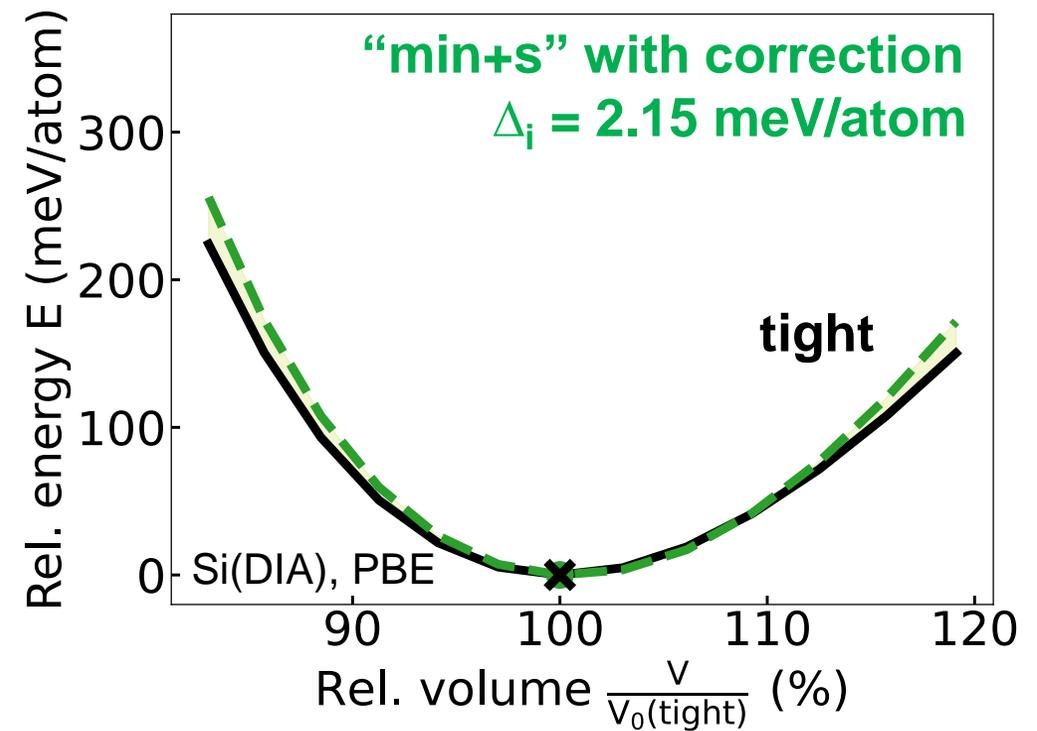
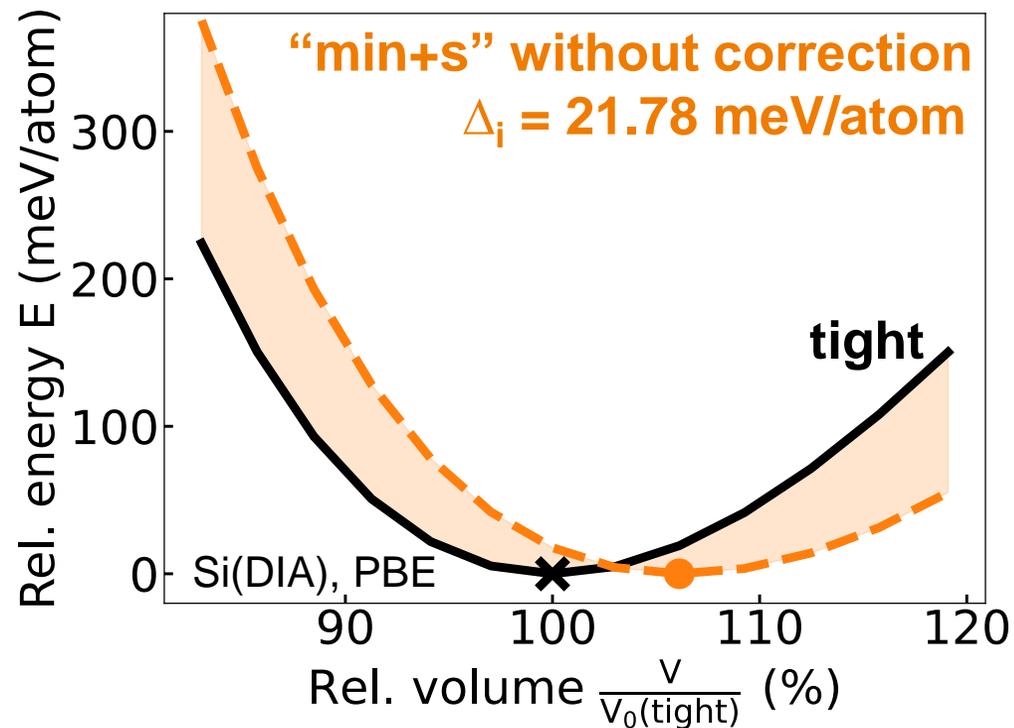




CORRECTION TO RECOVER ACCURATE GEOMETRIES

OBJECTIVE OF THE CORRECTION

Increase similarity between the corrected "min+s" and "tight" E-V curve



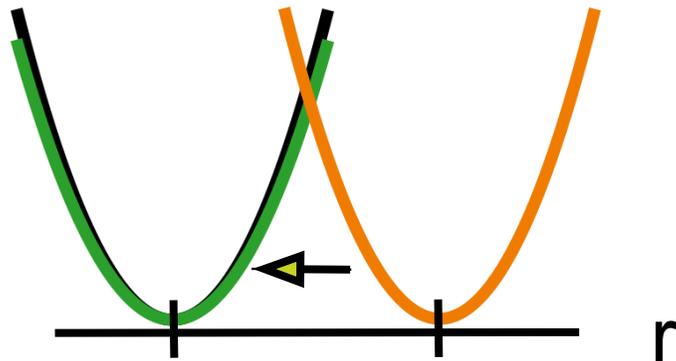


CORRECTION TO RECOVER ACCURATE GEOMETRIES

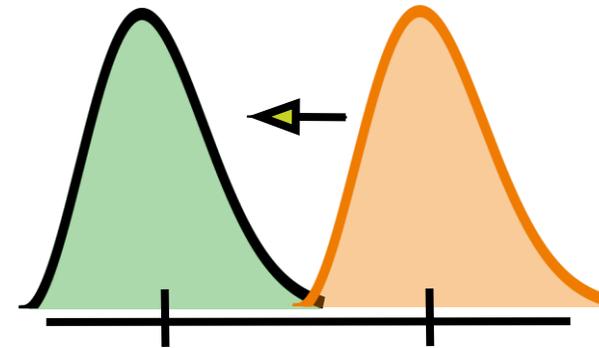
CHARACTERISTICS OF THE CORRECTION

Linear correction is most minimally-invasive [3]

E



correct equilibrium bond lengths



intact statistical ensemble

$$E_{\text{total}} = E_{\text{small basis}} + E_{\text{correction}}$$



CORRECTION TO RECOVER ACCURATE GEOMETRIES

MINIMALLY INVASIVE LINEAR CORRECTION

Proposed method

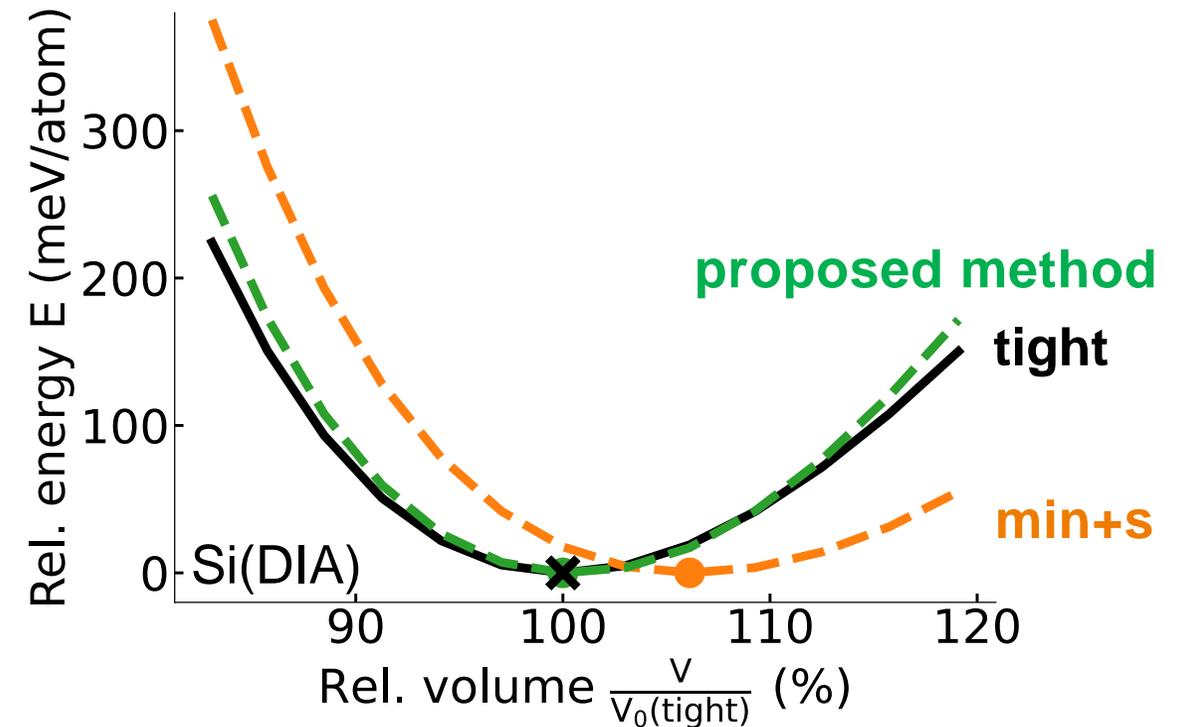
$$E_{\text{total}} = E_{\text{small basis}} + E_{\text{correction}}$$

$$E_{\text{correction}} = \frac{1}{2} \sum_A^{\text{Nunit}} \sum_{B \neq A}^{\text{Nsuper}} e_{AB}$$

$$e_{AB} = s(r_{AB} - r_{\text{cut}}) f_{\text{switch}}(r_{AB}, r_{\text{cut}})$$

with correction strength s

Proposed method E-V curve





FITTING OF ELEMENT DEPENDENT CORRECTION STRENGTH S

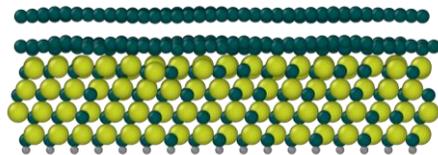
FITTING SET

Transferability to different bonding situations

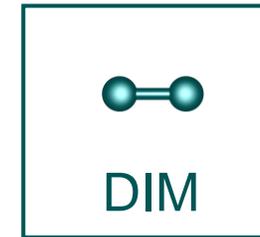
fitting set for $Z = 1 - 86$ [5]

surface

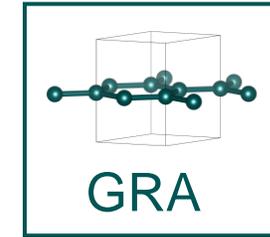
bulk



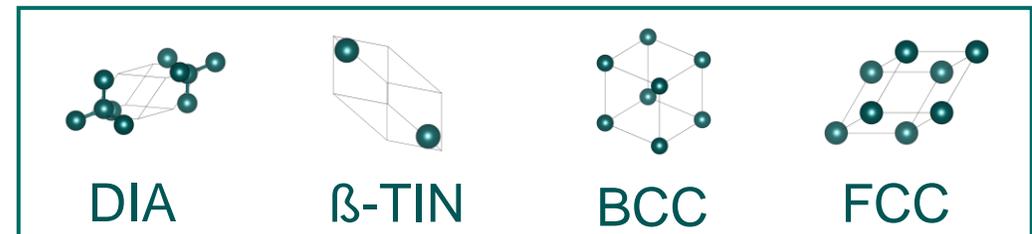
example: graphene on SiC(0001)[4]



non-periodic



semi-periodic



periodic

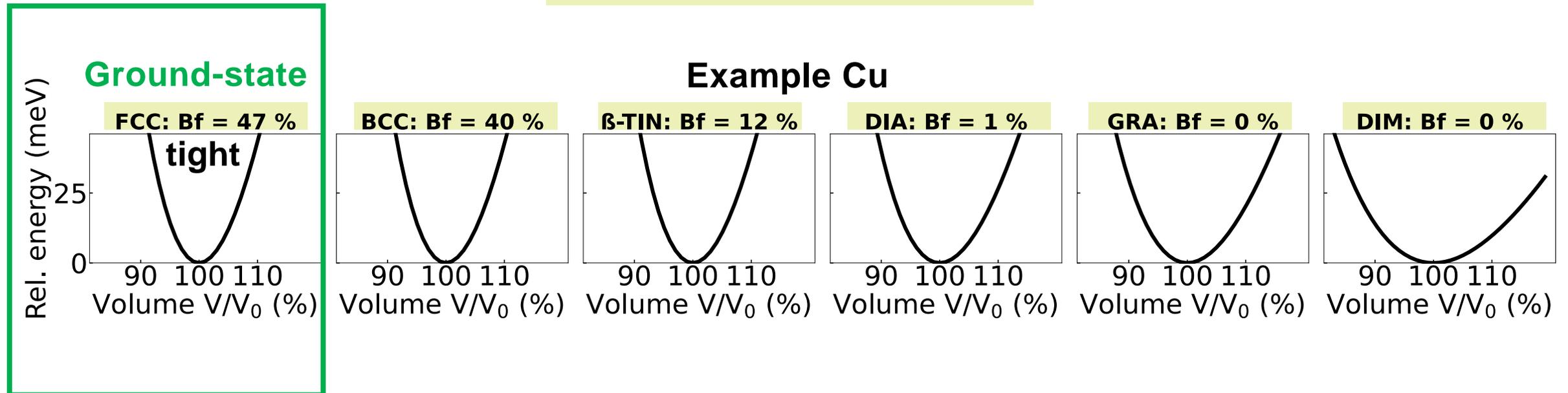


FITTING OF ELEMENT DEPENDENT CORRECTION STRENGTH S

FITTING SET

Energetic order given by Boltzmann factor

$$\text{Bf}(E_{0,i}) = e^{-\frac{(E_{0,i} - \min E_{0,i})}{kT=0.25\text{eV}}}$$



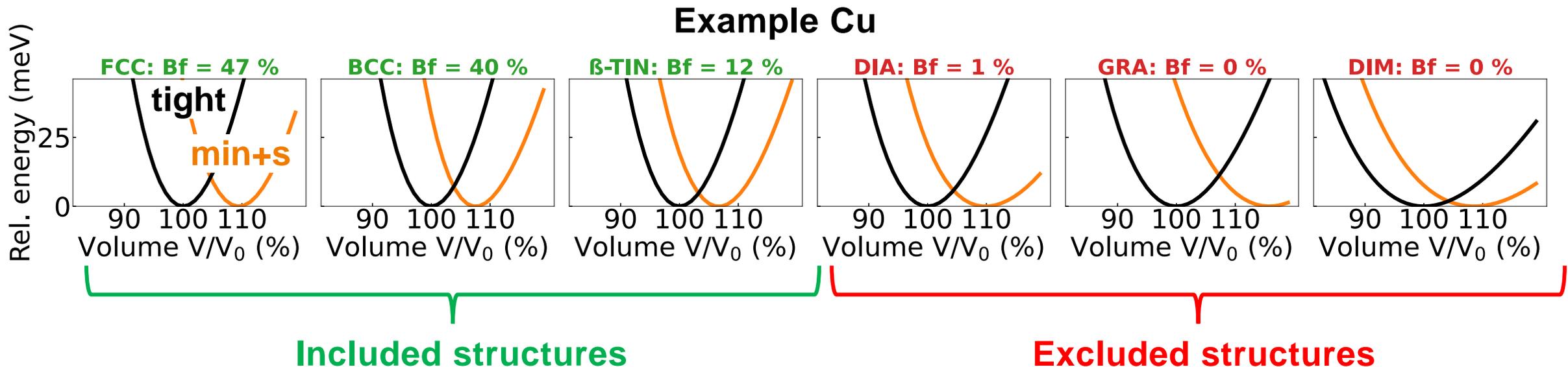


FITTING OF ELEMENT DEPENDENT CORRECTION STRENGTH S

FITTING SET

Include energetically most stable structures

$$Bf(E_{0,i}) = e^{-\frac{(E_{0,i} - \min E_{0,i})}{kT=0.25\text{eV}}} \geq 10\%$$



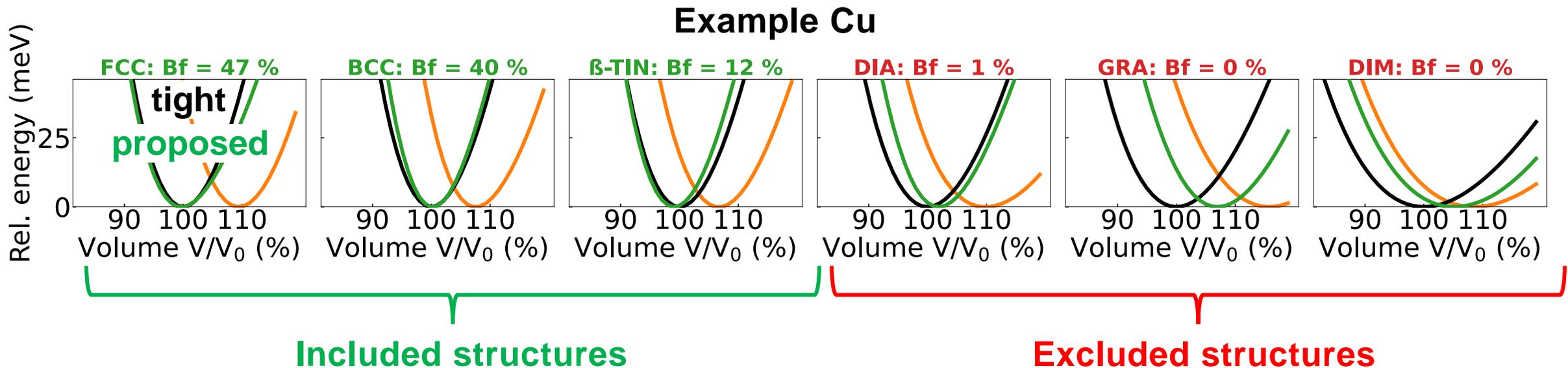


FITTING OF ELEMENT DEPENDENT CORRECTION STRENGTH S

E-V CURVES WITH FITTED CORRECTION STRENGTH

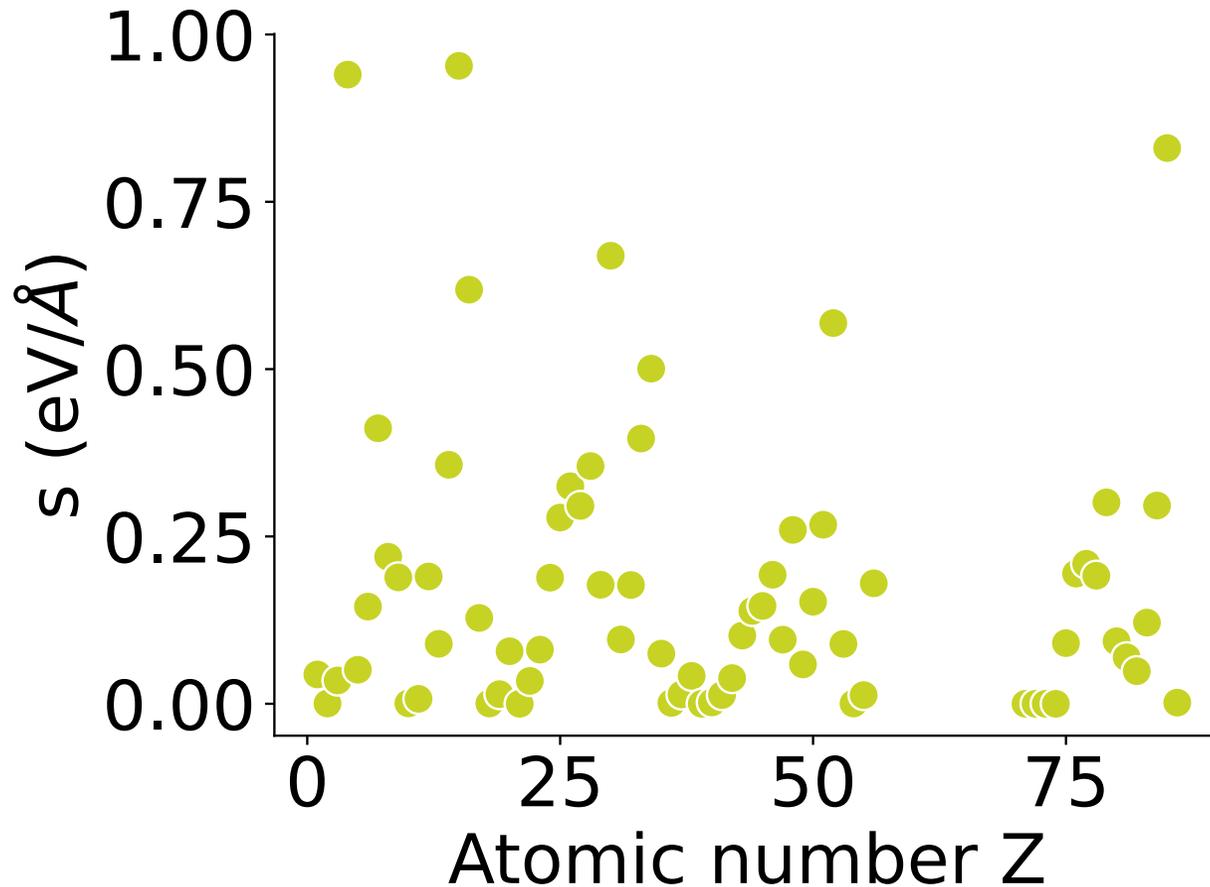
Include energetically most stable structures

$$Bf(E_{0,i}) = e^{-\frac{(E_{0,i} - \min E_{0,i})}{kT=0.25\text{eV}}} \geq 10\%$$



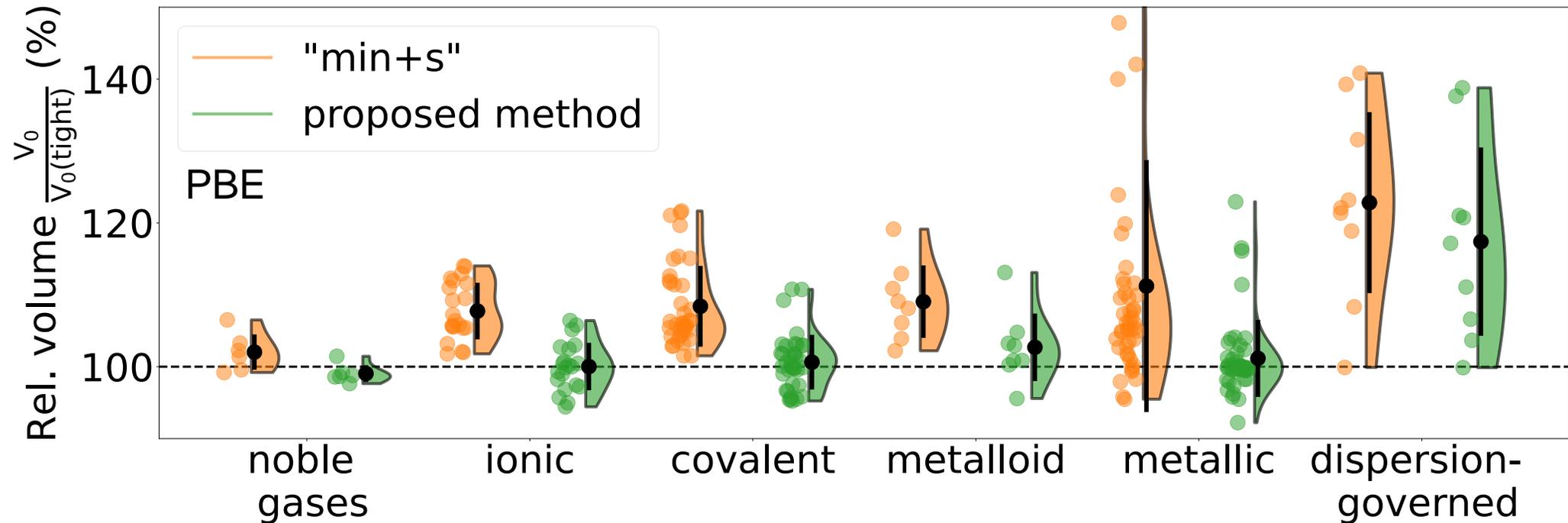


FITTED ELEMENT DEPENDENT CORRECTION STRENGTH S $Z = 1 - 86$ (EXCLUDING LANTHANIDES)



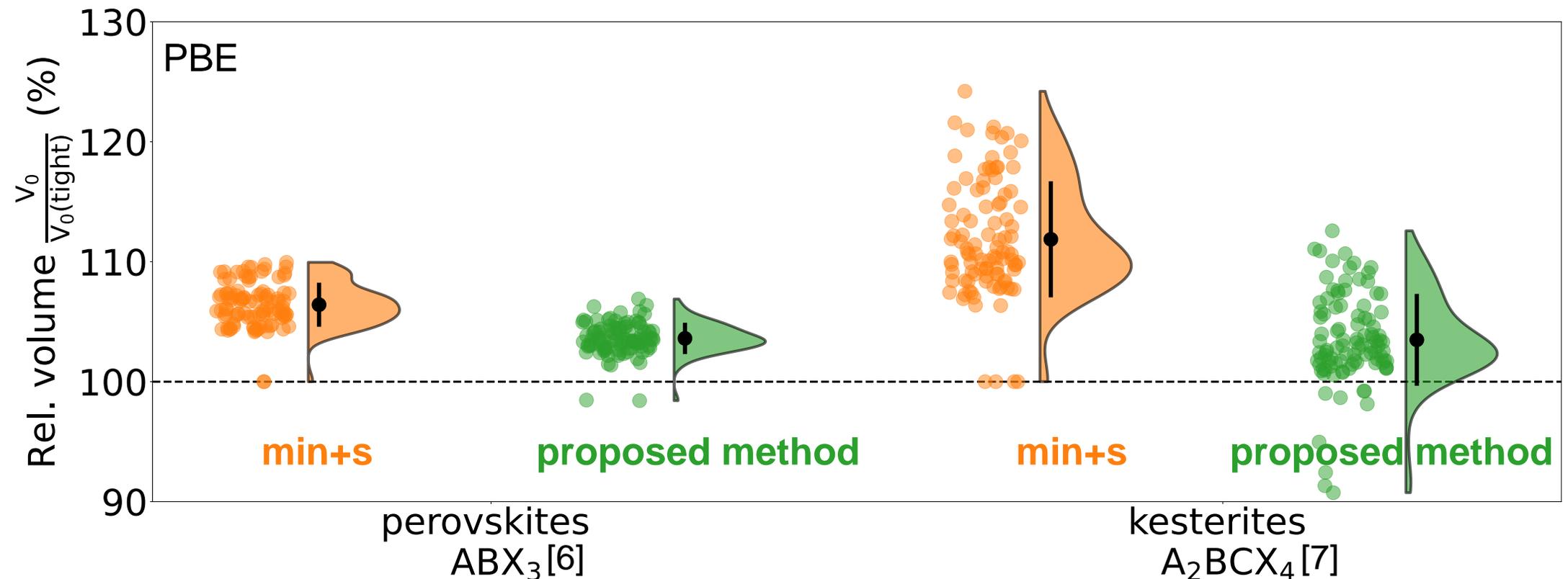


PERFORMANCE PROPOSED METHOD EQUILIBRIUM VOLUMES MONOELEMENTAL MATERIALS AND BINARY COMPOUNDS





CORRECTION TO RECOVER ACCURATE GEOMETRIES TERNARY AND QUATERNARY COMPOUNDS



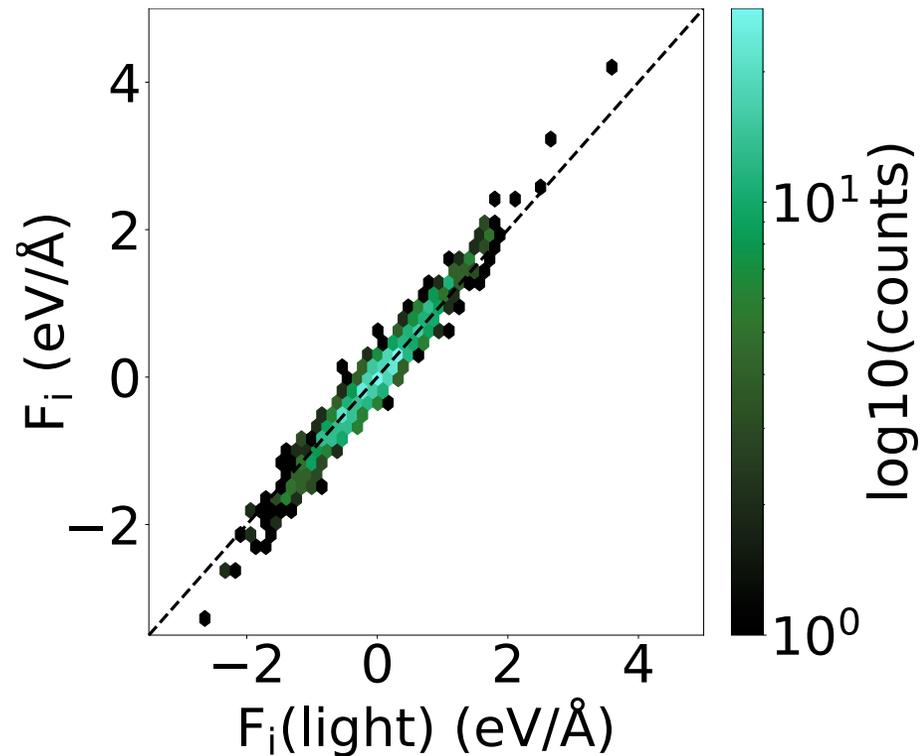
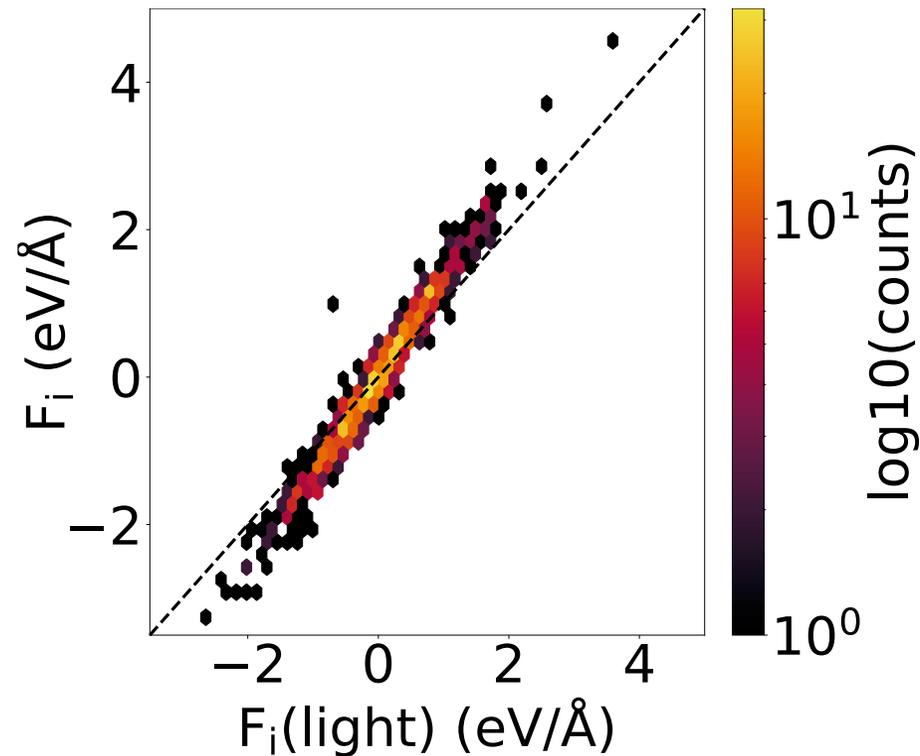


MOLECULAR DYNAMICS – FORCES

Cu, PBE, NPT $N = 256$ $P = 0$ eV/Å³ $T = 1600$ K

Small basis 'min+s' baseline

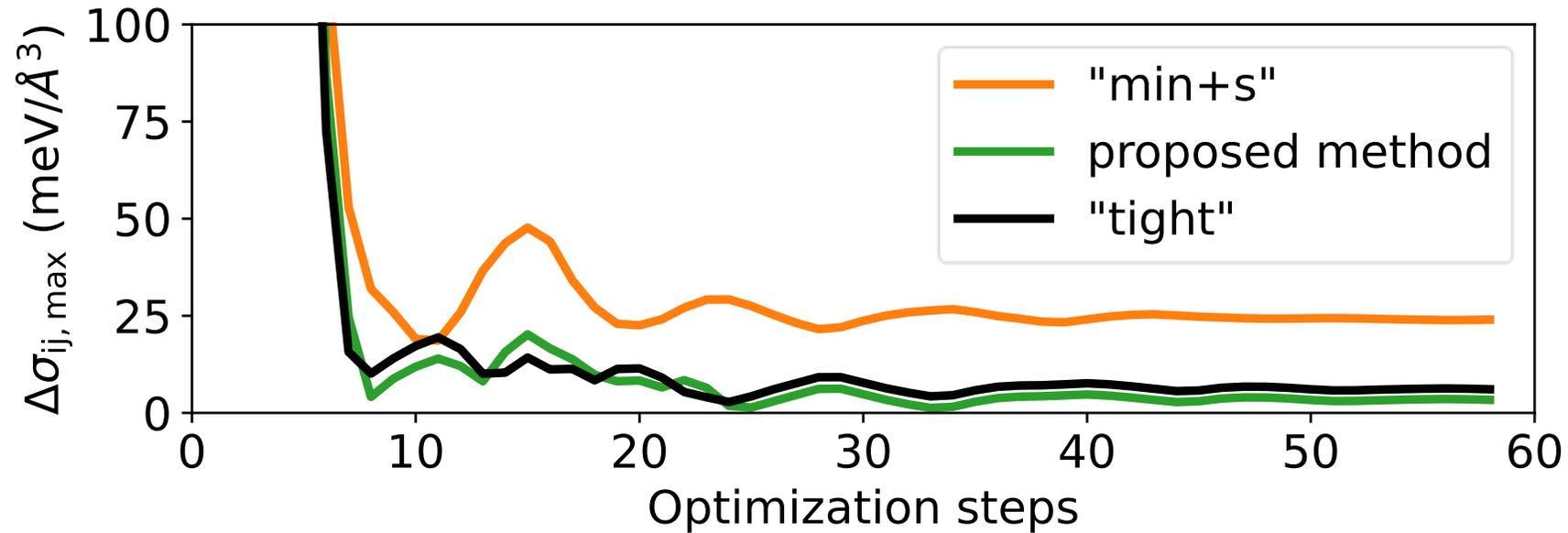
Proposed method





GEOMETRY OPTIMIZATION - STRESSES

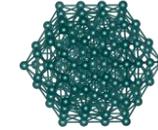
System: stretched + rattled Si(DIA) unitcell std 0.11 Angström, PBE



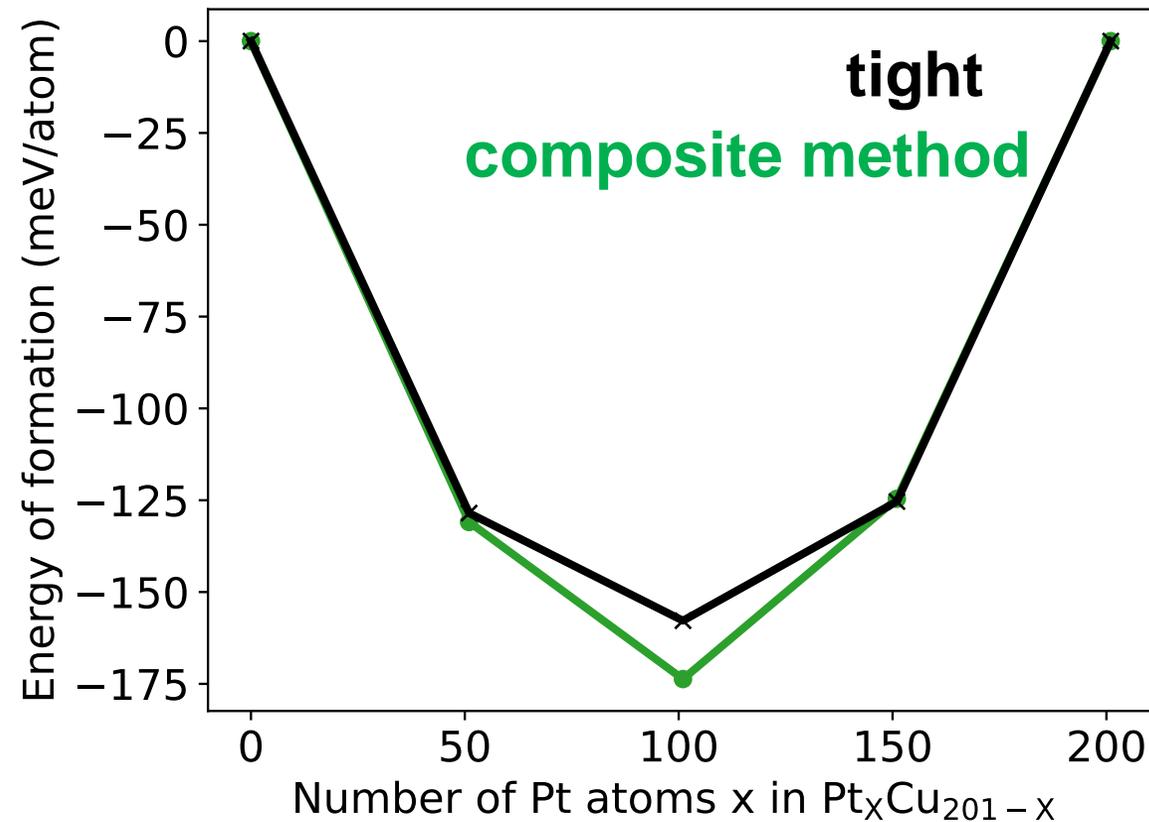


USE OF PROPOSED METHOD IN COMPOSITE METHODS

Nanoparticles $\text{Pt}_x\text{Cu}_{201-x}$ [8], PBE, $|\text{Fmax}| \leq 0.001 \text{ eV/\AA}^3$



Formation energy





STATUS SMALL BASIS DFT: PBE\”MIN+S” + CORRECTION

relative energies, forces, stresses for $Z = 1-86$ (excluding lanthanides)

Application areas

- **systems with hundreds of atoms**
speed-up MD, pre-relaxations and geometry optimizations etc.
use in composite methods
- **systems with ≥ 1000 of atoms**
enable large-scale geometry optimization at DFT level

